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1. Statistically estimating path delay fault coverage in combinational circuit
Zhang, Z.; McLeod, R.D.; Miller, D.M.; Zhang, S.;
Communications, Computers, and Signal Processing, 1995. Proceedings. IEEE
Conference on
17-19 May 1995 Page(s):461 - 464
Digital Object Identifier 10.1109/PACRIM.1995.519569

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